

Notice of References Cited	Application/Control No. 10/659,481		Applicant(s)/Patent Under Reexamination DILLON ET AL.	
	Examiner SARGON N. NANO		Art Unit 2157	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0043600	11-2001	Chatterjee et al.	370/390
*	B	US-2003/0195940	10-2003	Basu et al.	709/213
*	C	US-6,834,330	12-2004	Yechiel, Yochai	711/137
*	D	US-2003/0037041	02-2003	Hertz, Frederick S. M.	707/1
*	E	US-2002/0176361	11-2002	Wu et al.	370/231
*	F	US-2002/0116473	08-2002	Gemmell, David J.	709/219
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.